



#### **General Information**



\*Capital:797,828K NTD (~26 Million USD)

\*Operation Sites:

\*Head Quarter: Kaohsiung, Taiwan

\*Taipei Factory: Taipei, Taiwan

\*Shanghai Sales office: Shanghai, China.

\*Dong Guan Factory: Guan Dong, China.

\*Wuxi Factory: Wuxi, China





### **History & Achievements**

- > 1994 : E&R was established
- > 1996 : Fully automatic IC laser marking machine, BLAZON-1600, was launched
- > 1998 : Plasma Cleaner, Plasmax-800, for BGA applications, was launched
- > 1998 : Business of carrier tape for SMD was start-up
- > 2001 : Awarded by Philips semiconductor as the best supplier of equipment
- > 2003 : Awarded by OSE as the best supplier of equipment
- > 2007 : Awarded by Philips semiconductor as the best supplier of carrier tape
- > 2008 : Market share of IC laser marking equipment was number one in Taiwan
- > 2008 : Market share of carrier tape was number one in China
- > 2009 : Pioneer of laser micromachining for applications of Silicon, ITO, ceramics and glass
- > 2010 : Awarded by ASE as the best supplier of equipment
- > 2014 : The only supplier of laser machine to the worldwide leading company of smart watch
- ➤ 2015 : IPO in Taipei Exchange
- 2016~: Laser wafer marker, laser wafer cutting machine, microwave plasma cleaner was launched



### **Company Scope (1)**

#### E& R Kaohsiung Taiwan

- Semiconductor Equipment: Laser Marker, Plasma Cleaner, SIP Laser cutting M/C. Laser Wafer cutting machine.
- FPC Equipment: Laser cutting/Drilling M/C, Film Laminators, Roll to Roll Handling system.
- LED Equipment : plasma cleaner, Ceramic Laser Driller, Ceramic Laser Marking M/C.
- Display Equipment: Laser patterning M/C, Laser Glass cutting M/C.





#### **Company Scope (2)**

#### E& R Taipei

 FPC (Flexible printing Circuit Board) and module manufacturing and sales



#### E& R Shanghai

· Sales and Services, China



Carrier Tape Manufacturing and Sales

#### E& R Wuxi

Carrier Tape Manufacturing and Sales







#### **Product Introduction**



Core

Core Technologies





**FPC Equipment** 

**SMD Packing Materials** 



#### Laser

# **Development Products Application**

	Products	Application
1	Laser Strip Marker	IC Marking for final product.
2	Laser wafer marker	IC Marking for in-process traceability.
3	Laser Package cutting Machine	Cut the whole substrate into individual units.
4	FPC Laser Cutting Machine	FPC cutting
5	Laser Wafer Scribing/Cutting Machine	Cut the whole wafer into individual units.

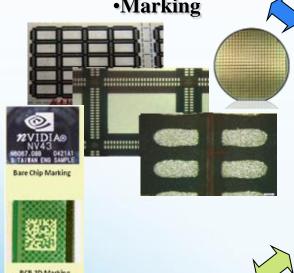


#### **Key application, Laser**



Micro via drilling

Marking



Semiconductor

**LED** 

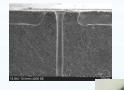
**Application** 

FPC/HDI

Pane1



- Cutting/scribing
- Micro via drilling



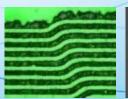


- •glass cutting
- •ITO patterning



Cutting











# **Laser Wafer Cutting Machine**





# **Laser Wafer Marking Machine**





# **Laser FPC Rapid Cut-L200D**





# Plasma Development Products Application

	Products	Application
1	Batch Type RF Cleaner	Surface activation, Remove metal oxide, improve bondability
2	IN-Line RF Cleaner	Surface activation, Remove metal oxide, improve bondability
3	Microwave Plasma Cleaner	Surface activation, Remove metal oxide, improve bondability
4	Microwave Etcher De-flash · Descum	Remove epoxy residue, Remove PR residue.
5	Microwave Plasma Dicing/THIN	Cut the whole wafer into individual units



#### Key application, plasma



LF, RF and Micro-Wave all available for request

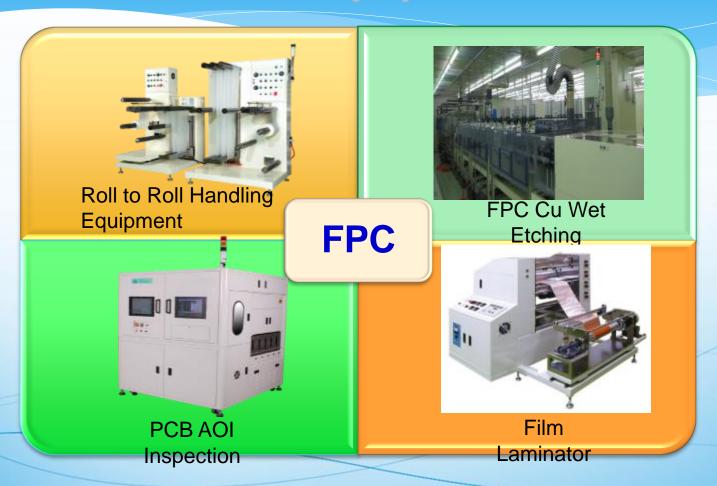


#### Microwave Plasma Cleaner Plasmax-MW 300





# **FPC Equipment**



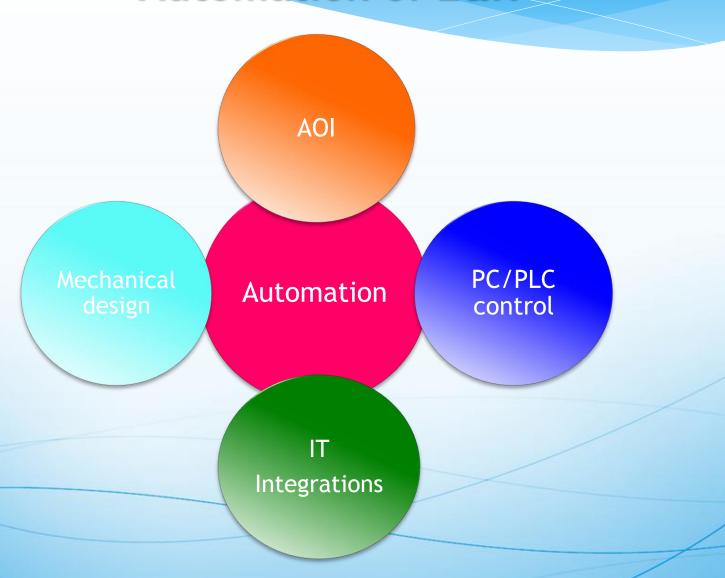


#### **Core Technical**

- Automation of E&R
  - > IT Integrations



# **Automation of E&R**





# New Technology For Wafer Level

# Wafer Back Side Marker for 8"/12" Silicon Wafer



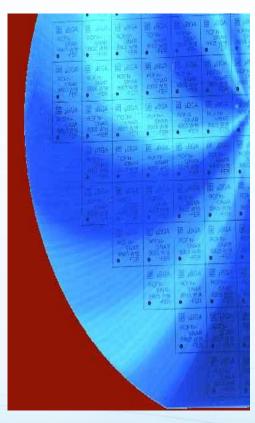
8", 12" black coated wafer



6", 8" mesh wafer



6", 8" thin metal coated wafer







12" gold coated wafer



8", 12" SIN Silicon wafer



8", 12" polish silicon with tape before marking



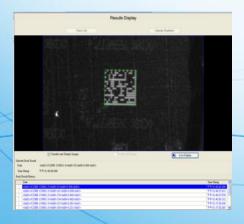
8", 12" bare Si grinded

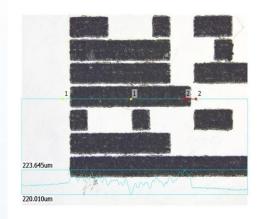


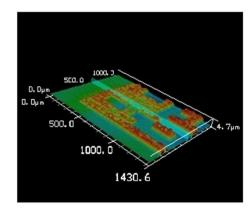
# Wafer Marker for 8" Glass Substrate

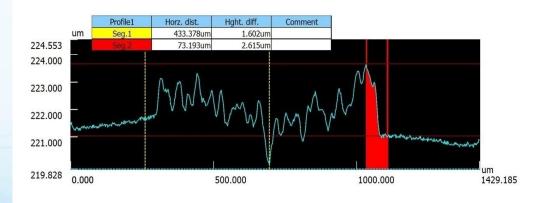








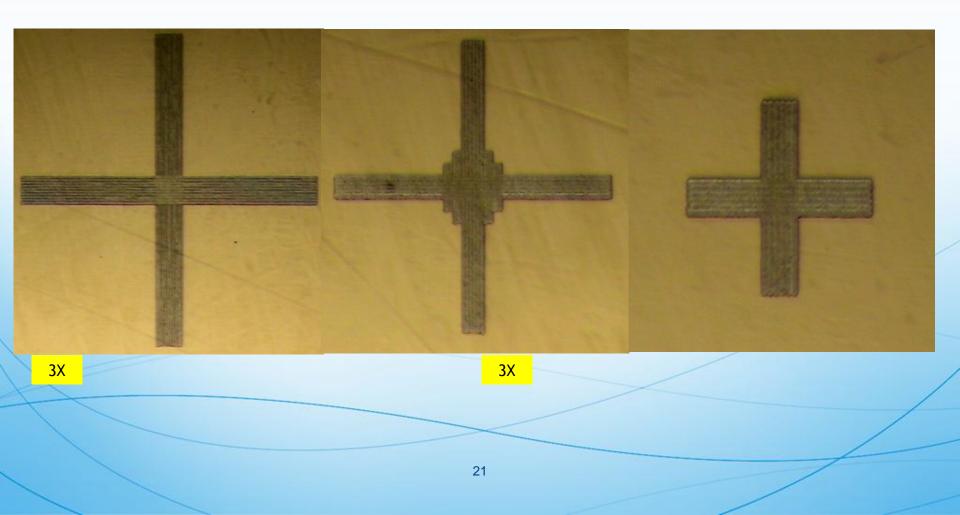




- 1. 2x2 2D Full Type And Good Reading from 2D
- 2. No "HAZ" and slag found



# Glass Inner Alignment Mark



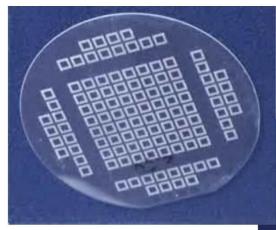


# Wafer Cutting & Scribing



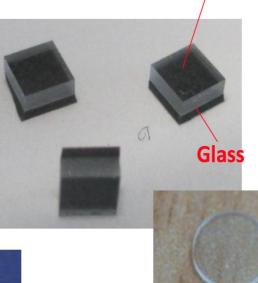
#### Wafer Level cutting & Scribing

- > Straight & round cut trajectories
- Cutting speed : >200mm/sec, straight edge
- ➤ Chipping : <10um, straight edge
- ➤ Roughness, sidewall : Ra <1um
- ➤ Thickness of glass : 0.3~1.1mm





#### **Molding compound**

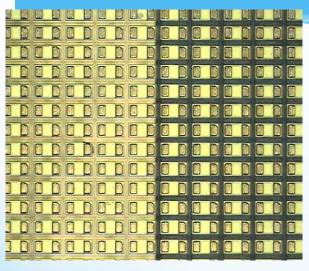




5mm



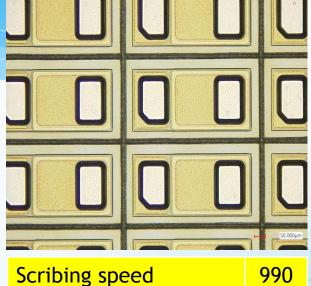
#### Wafer Level cutting & Scribing



➤ Die Size: 1.1x0.7mm
➤ Dicing street: 90um

		U		U	
00			0	0	
	00	0	D	D	0
00	00		D	D	
00	00			0	0
				0	
					50.000µm
Scribi	ng snee	h		18	4

Scribing speed	184
(mm/sec)	
Trench width(um)	76.4
Trench depth(um)	2.3

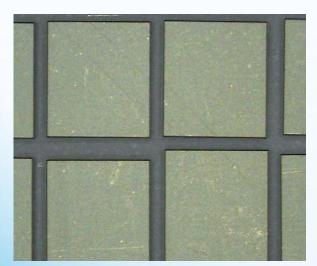




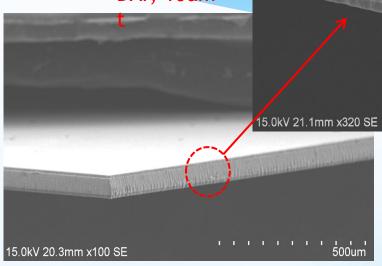
# Wafer Level cutting & Scribing

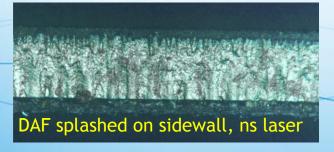
➤Si cutting speed : >150 mm/s

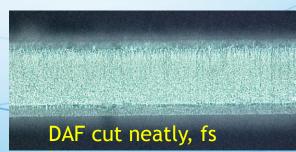
➤ roughness: Ra < 1um</p>



Polymer, 10um t
Si, 50um
DAF, 10um



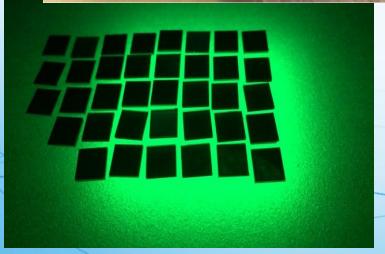


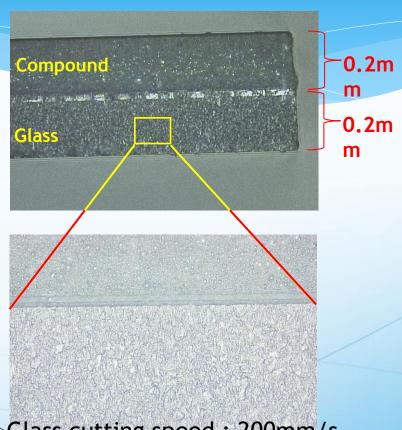




#### Internal Scribing .. Fan-out wafer







➤Glass cutting speed: 200mm/s

≻roughness : Ra < 1um

50.000µm



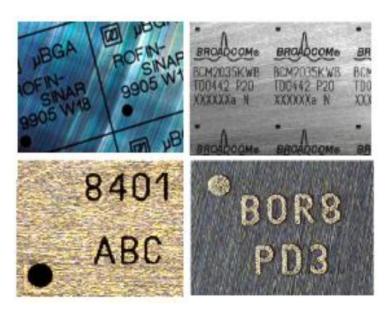
# Wafer Marking



#### Wafer Laser Marking

- > Features
  - ✓ Chip marking & Wafer ID marking
  - ✓ Through tape marking
  - ✓ Bare wafer marking : Grinding/Polishing & metal surface
  - √ Warpage eliminator







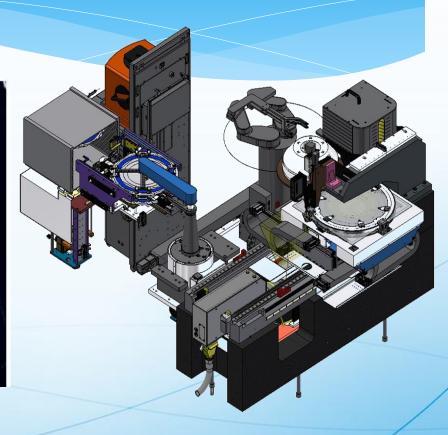


#### Wafer Laser Marking

➤Through-tape marking

ENRA4	0.8
ENRA4	0.6
AND THE RESERVE OF THE PARTY OF	0.5
	0.4
ENRAL	0.3
800MM	1/8

ENRA4	0.6
ENRA4	0.5
ENRA4	U.4
ENRA4	U.3
800MI	M/S

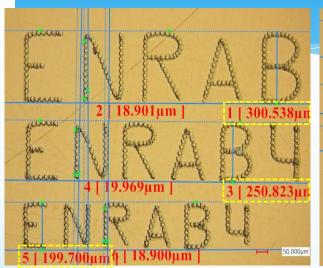


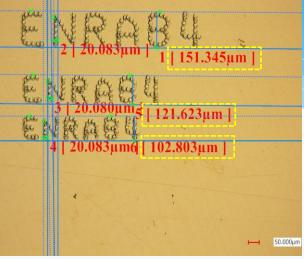
Before tape remove

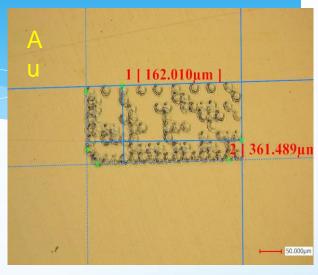
After tape remove



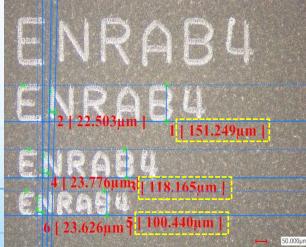
#### Wafer Laser Marking .. Tiny Character - 0.1mm















# Wafer Plasma



**Equipment overview** 





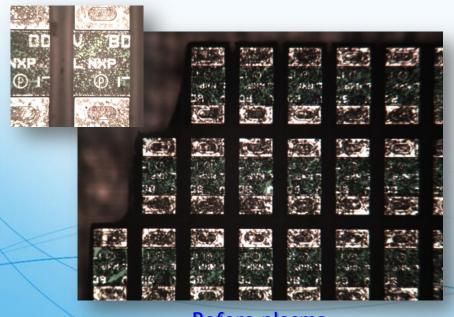


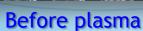
**CRM-300R** 

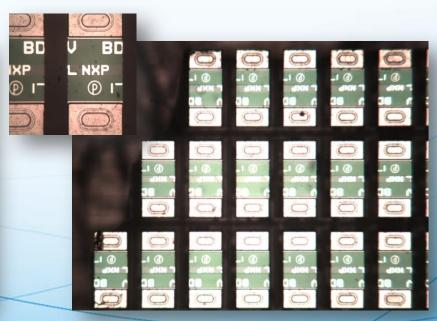


### Compound Residue Removal - substrate

Residue must be thoroughly removed from bumps, but still keep dicing streets fully covered with compound.



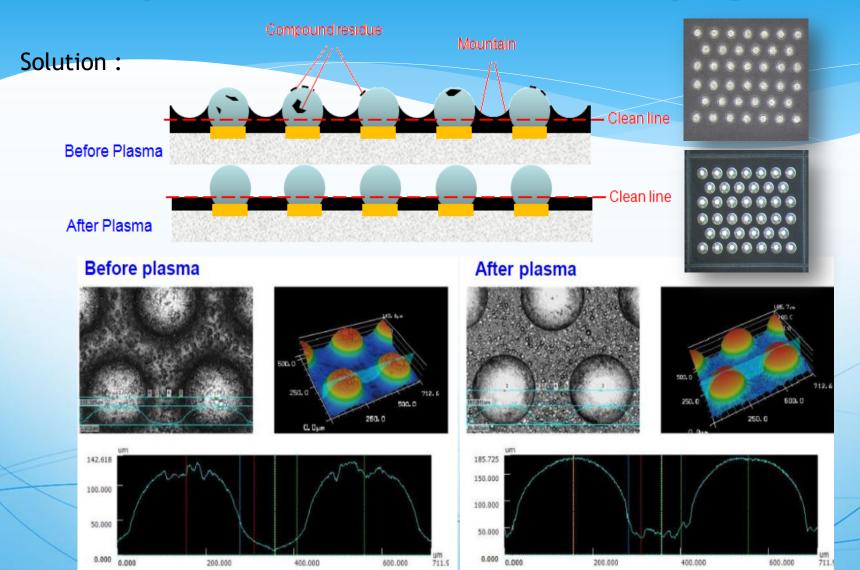




After plasma



#### Compound Residue Removal - Bumping wafer





#### Compound Residue Removal - Copper Pillar

• For bumping process of copper pillar, photoresist residue can't be fully removed by wet chemicals and remains on the UBM pads. These residue will impede the subsequent copper electroplating process and cause defects.

**CRM-300** Series can fully remove residue to raise the yield of copper pillar bumping, through descum process.

